



Final Product/Process Change Notification

Document # : FPCN21457X

Issue Date: 24 February 2017

Title of Change:	Transfer of the PTIC Fab process from ON Semiconductor facility in Burlington, Canada to ON Semiconductor facility in Niigata, Japan		
Proposed first ship date:	2 June 2017		
Contact information:	Contact your local ON Semiconductor Sales Office or <Scott.Haddow@onsemi.com>		
Samples:	Samples have been sent to customer since Oct 20, 2016		
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Scott.Haddow@onsemi.com>		
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.		
Change Part Identification:	Affected product will be identified with date code		
Change category:	☒ Wafer Fab Change ☐ Assembly Change ☐ Test Change ☐ Other _____		
Change Sub-Category(s):	☒ Manufacturing Site Change/Addition ☐ Manufacturing Process Change ☐ Material Change ☐ Product specific change ☐ Datasheet/Product Doc change ☐ Shipping/Packaging/Marking ☐ Other: _____		
Sites Affected:	☐ All site(s) ☐ not applicable ☒ ON Semiconductor site(s) : ON Burlington, Canada ON Niigata, Japan ☐ External Foundry/Subcon site(s)		
Description and Purpose:			
PTIC Fab process has been moved from ON Semiconductor facility in Burlington Canada to the ON Semiconductor facility in Niigata Japan. The purpose of this change is to increase the capacity.			

**Reliability Data Summary:**

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta= _125_°C, 100 % max rated Vcc =20V	5 hrs	0/240
HTSL	JESD22-A103	Ta= _150_°C	1000 hrs	0/240
TC	JESD22-A104	Ta= -_65_°C to +_125_°C	500 cyc	0/240
HAST Replaced by THB	JESD22-A110 Replaced by JESD22-A101-B	130°C, 85% RH, 18.8psig, bias Replaced by 85°C, 85% RH, bias=12V	500 hrs	0/240
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	Bridged Gen 4.1 Burlington DTE 1620 0/120
PC	J-STD-020 JESD-A113	MSL 1 @ 85 °C, 85% RH	168 hrs	0/480
CA	On Semi# 12MRM94918A	Construction Analysis, comparison 1 die each	Unused die	0/1

Electrical Characteristic Summary:

The process transfer was copy exact. There are no changes to the datasheet specifications

List of affected Standard Parts:

Part Number	Qualification Vehicle
TCP-4112UB-DT	TCP-4127UA-DT TCP-4182UB-DT TCP-4147UB-DT
TCP-4118UB-DT	
TCP-4127UB-DT	
TCP-4127UA-DT	
TCP-4133UB-DT	
TCP-4139UB-DT	
TCP-4147UB-DT	
TCP-4156UB-DT	
TCP-4168UB-DT	
TCP-4182UB-DT	
TCP-4133UA-DT	